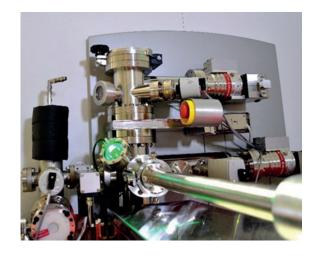


Acknowledgements





Bundesministerium für Bildung und Forschung

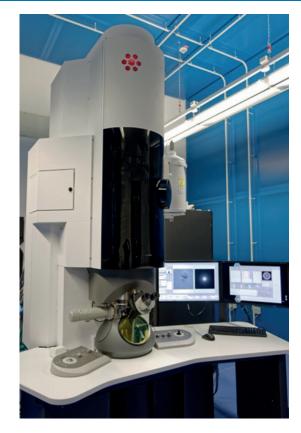


Contact

Please send your registration and request to: **TEM-APT@mpie.de**

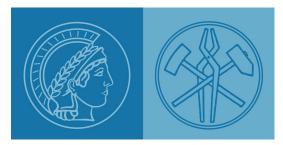
More information about the institute **www.mpie.de**

We look forward to greeting you in Düsseldorf!Local OrganizersAdvisory BoardParaskevas KontisGerhard DehmThorsten MeinersBaptiste GaultZirong PengDierk RaabeYasmin Ahmed SalemChristina ScheuSiyuan ZhangSiyuan Zhang



Opening Symposium for Advanced S/TEM and APT Facilities

5 - 6 November 2018



Max-Planck-Institut für Eisenforschung GmbH

Opening symposium for advanced (S)TEM and APT facilities at MPIE		Monday, 5 th November	Tuesda	ay, 6 th November
The Max-Planck-Institut für Eisenforschung GmbH (MPIE) is happy to announce the opening symposium for advanced (S)TEM and APT facilities, scheduled on 5 th – 6 th November 2018.	8:15 - 9:00	Registration	9:15 - 10:00	Balancing spatial, energy and mo-
	9:00 - 9:05	<i>Welcome Words</i> Gerhard Dehm, MPIE		<i>mentum resolutions in STEM-EELS</i> Quentin Ramasse, EPSRC National Research Facility for Advanced Elec-
We are pleased to celebrate this inauguration by a stimulating scientific colloquium with renowned experts and friends from all over the world.	9:05 - 9:15	<i>Welcome Words</i> Susanne Schneider-Salomon, NRW- Ministerium für Kultur und Wissenschaft	10:00 - 10:45	tron Microscopy Application of correlative micros- copy for investigating defects in
 Topics of the symposium will include: Development of advanced APT and (S)TEM techniques New horizons in correlative (S)TEM and APT Application to catalysis and energy materials Interface science 	9:15 - 10:00	Spherical and chromatic abberation corrected TEM: state-of-the-art and future		<i>chalcogenide materials</i> Oana Cojocaru-Mirédin, RWTH Aachen University
		Joachim Mayer, Ernst Ruska-Centre	10:45 - 11:15	Coffee break
	10:00 - 10:45	Developments in FEM since 1935 from the 2018 MPIE perspective Leigh Stephenson, MPIE	11:15 - 12:00	Synergies in correlating aberration- corrected STEM with APT Christian Liebscher, MPIE
	10:45 - 11:15	Coffee break	12:00 - 12:45	Opportunities offered by the serial
	11:15 - 12:00	High precision and in situ TEM stud- ies of strain induced effects on cata- lytic activity and electrical properties Eva Olsson, Chalmers University		and/or in situ combination of APT and (S)TEM Williams Lefebvre, GPM, CNRS, Uni- versité et INSA de Rouen
	12:00 - 12:45		12:45 - 14:00	Lunch break
		<i>catalyst materials by APT</i> Tong Li, Ruhr-Universität Bochum	14:00 - 14:45	Retrieving atomic structure from TEM data: a combined effort of
[100]γ/κ ABF-STEM (a) [010]γ/κ [001]γ/κ 50 nm HAADF-STEM (b) - Fe APT (c) - Al - Mn - ≥ 9 at.% C	12:45 - 14:00	Lunch break		high-end instrumentation and com- putation
	14:00 - 14:45	The role of interface complexions on processing ceramic matrix nanocom-		Christoph Koch, Humboldt-Universität zu Berlin
		<i>posites</i> Wayne D. Kaplan, Technion-Israel	14:45 - 15:30	APT simulations: beyond electro- statics
	14:45 - 15:30	Revealing solute grain boundary specificity through cross-correlative		Christian Oberdorfer, Ohio State University
		precession electron diffraction - APT Gregory B. Thompson, University of Alabama	15:30 - 15:40	<i>Concluding remarks</i> Dierk Raabe, MPIE
	15:30 - 16:00	Coffee break	15:40 - 16:00	Coffee Break
	16:00 - 17:30	Lab tour	16:00	End

Dinner

18:30

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